

QUERY CONTROL FORM

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Application No. 09/629407
Examiner-GAUJ Bruce - 2882

Prepared by

1/8/04

Tracking Number 05875029

Examiner-GAUJ Bruce - 2882

Date _____

1/8/04

Week Date

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|----------------------|------------------------|--------------------|----------------|
| a. Serial No. | f. Foreign Priority | k. Print Claim(s) | p. PTO-1449 |
| b. Applicant(s) | g. Disclaimer | l. Print Fig. | q. PTOL-85b |
| c. Continuing Data | h. Microfiche Appendix | m. Searched Column | r. Abstract |
| d. PCT | i. Title | n. PTO-270/328 | s. Sheets/Figs |
| e. Domestic Priority | j. Claims Allowed | o. PTO-892 | t. Other |

SPECIFICATION

- a. Page Missing
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- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
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INFORMATION DISCLOSURE CITATION <i>(Use additional sheets if necessary)</i> 	Docket Number (Optional)	Application Number
	TWI-10820	09/629,407
	Applicant(s)	
	Alfan Rosenzweig et al.	
	Filing Date	Group Art Unit
	August 1, 2000	2876

U.S. PATENT DOCUMENTS

* EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
CA	WO 91/71325	09/27/2001	PCT	G01N	23/00		

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

CB	E. Loken et al., "Growth monitoring of W/Si X-ray multilayers by X-ray reflectivity and Kinetic ellipsometry," <i>SPIE</i> , Vol. 2253, November 1994, pp. 327-332.

Examiner	Date Considered
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include Copy of this form with next communication to applicant.	

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